

ADuM2200/ADuM2201

Dual-Channel Digital Isolators, 5 kV

FEATURES

- ▶ High isolation voltage: 5000 V rms
- ▶ Enhanced system-level ESD performance per IEC 61000-4-x
- ▶ Low power operation
 - ▶ 5 V operation
 - ▶ 1.6 mA per channel maximum at 0 Mbps to 1 Mbps
 - ▶ 3.7 mA per channel maximum at 10 Mbps
 - ▶ 3.3 V operation
 - ▶ 1.4 mA per channel maximum at 0 Mbps to 1 Mbps
 - ▶ 2.4 mA per channel maximum at 10 Mbps
- ▶ 3.3 V/5 V level translation
- ▶ High temperature operation: 105°C and 125°C options
- ▶ High data rate: dc to 10 Mbps (NRZ)
- ▶ Precise timing characteristics
 - ▶ 3 ns maximum pulse width distortion
 - ▶ 3 ns maximum channel-to-channel matching
- ▶ High common-mode transient immunity: >25 kV/μs
- ▶ [16-lead SOIC wide body package version \(RW-16\)](#)
- ▶ [16-lead SOIC wide body enhanced creepage version \(RI-16-2\)](#)
- ▶ [Safety and regulatory approvals](#)
- ▶ ▶ UL 1577
 - ▶ $V_{ISO} = 5000$ V rms for 1 minute.
 - ▶ IEC/EN/CSA 62368-1
 - ▶ IEC/CSA 60601-1
 - ▶ IEC/CSA 61010-1
 - ▶ CQC GB4943.1
 - ▶ DIN EN IEC 60747-17 (VDE 0884-17)
 - ▶ $V_{IORM} = 645$ V peak
- ▶ Qualified for automotive applications

APPLICATIONS

- ▶ General-purpose, high voltage, multichannel isolation
- ▶ Medical equipment
- ▶ Power supplies
- ▶ RS-232/RS-422/RS-485 transceiver isolation
- ▶ Hybrid electric vehicles, battery monitors, and motor drives

GENERAL DESCRIPTION

The ADuM2200/ADuM2201¹ are 2-channel digital isolators based on Analog Devices, Inc., *iCoupler*® technology. Combining high speed CMOS and monolithic air core transformer technology, these isolation components provide outstanding performance characteristics that are superior to alternatives such as optocoupler devices.

By avoiding the use of LEDs and photodiodes, *iCoupler* devices remove the design difficulties commonly associated with optocouplers. Typical optocoupler concerns regarding uncertain current transfer ratios, nonlinear transfer functions, and temperature and lifetime effects are eliminated with the simple *iCoupler* digital interfaces and stable performance characteristics. The need for external drivers and other discrete components is eliminated with these *iCoupler* products. Furthermore, *iCoupler* devices consume one-tenth to one-sixth the power of optocouplers at comparable signal data rates.

The ADuM2200/ADuM2201 isolators provide two independent isolation channels in two channel configurations with data rates up to 10 Mbps (see the [Ordering Guide](#)). Both parts operate with the supply voltage on either side ranging from 3.0 V to 5.5 V, providing compatibility with lower voltage systems, as well as enabling voltage translation functionality across the isolation barrier. The ADuM2200/ADuM2201 isolators have a patented refresh feature that ensures dc correctness in the absence of input logic transitions and during power-up/power-down conditions.

Similar to the [ADuM3200/ADuM3201](#) isolators, the ADuM2200/ADuM2201 isolators contain various circuit and layout enhancements that provide increased capability relative to system-level IEC 61000-4-x testing (ESD, burst, and surge). The precise capability in these tests for either the ADuM3200/ADuM3201 or ADuM2200/ADuM2201 products is strongly determined by the design and layout of the user's board or module. For more information, see the [AN-793 Application Note](#), *ESD/Latch-Up Considerations with iCoupler Isolation Products*.

¹ Protected by U.S. Patents 5,952,849; 6,873,065; 6,903,578; and 7,075,329. Other patents pending.

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REVISION HISTORY**1/2025—Rev. G to Rev. H**

Changes to Features Section.....	1
Moved Figure 1 and Figure 2.....	3
Changes to Regulatory Information Section and Table 14.....	9
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Changed Insulation Characteristics (DIN V VDE V 0884-10 (VDE V 0884-10):2006-12) Section to DIN EN IEC 60747-17 (VDE 0884-17) Insulation Characteristics Section.....	10
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Changes to Table 19.....	12
Deleted Table 20 and Table 21; Renumbered Sequentially.....	12
Changes to Insulation Lifetime Section.....	18
Deleted Figure 16 to Figure 18; Renumbered Sequentially.....	18
Added Number of Inputs, Maximum Data Rate, Maximum Propagation, and Maximum Pulse Width Distortion Options.....	19

FUNCTIONAL BLOCK DIAGRAMS

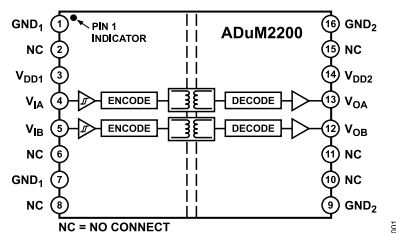


Figure 1. ADuM2200

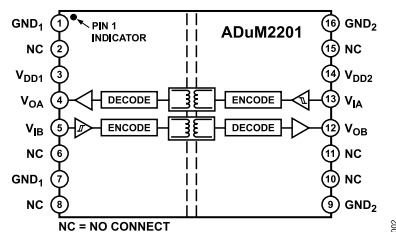


Figure 2. ADuM2201

SPECIFICATIONS

ELECTRICAL CHARACTERISTICS—5 V OPERATION

All voltages are relative to their respective grounds. $4.5\text{ V} \leq V_{DD1} \leq 5.5\text{ V}$, $4.5\text{ V} \leq V_{DD2} \leq 5.5\text{ V}$. All minimum/maximum specifications apply over the entire recommended operation range, unless otherwise noted. All typical specifications are at $T_A = 25^\circ\text{C}$, $V_{DD1} = V_{DD2} = 5.0\text{ V}$.

Table 1.

		A Grade			B Grade				
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit	Test Conditions/Comments
SWITCHING SPECIFICATIONS									C _L = 15 pF, CMOS levels
Pulse Width	PW	1000			100			ns	Within PWD limit
Data Rate				1			10	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}	20		150	20		50	ns	50% input to 50% output
Pulse Width Distortion	PWD			40			3	ns	t _{PLH} - t _{PHL}
Change vs. Temperature						5		ps/°C	
Propagation Delay Skew	t _{PSK}			100			15	ns	Between any two units
Channel Matching									
Codirectional	t _{PSKCD}			50			3	ns	
Opposing Directional	t _{PSKOD}			50			15	ns	

Table 2.

		1 Mbps—A Grade, B Grade			10 Mbps—B Grade			
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit
SUPPLY CURRENT (NO LOAD)								
ADuM2200	I _{DD1}		1.3	1.8		3.5	4.6	mA
	I _{DD2}		1.0	1.6		2.0	2.8	mA
ADuM2201	I _{DD1}		1.1	1.6		3.1	4.2	mA
	I _{DD2}		1.3	1.9		3.1	4.0	mA

Table 3.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
DC SPECIFICATIONS						
Logic High Input Threshold	V_{IH}	$0.7 V_{DDx}$			V	
Logic Low Input Threshold	V_{IL}			$0.3 V_{DDx}$	V	
Logic High Output Voltages	V_{OH}	$V_{DDx} - 0.1$	5.0		V	$I_{Ox} = -20\text{ }\mu\text{A}$, $V_{Ix} = V_{IxH}$
		$V_{DDx} - 0.5$	4.8		V	$I_{Ox} = -3.2\text{ mA}$, $V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V_{OL}		0.0	0.1	V	$I_{Ox} = 20\text{ }\mu\text{A}$, $V_{Ix} = V_{IxL}$
			0.2	0.4	V	$I_{Ox} = 3.2\text{ mA}$, $V_{Ix} = V_{IxL}$
Input Current per Channel	I_I	-10	+0.01	+10	μA	$0\text{ V} \leq V_{Ix} \leq V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	$I_{DDI(Q)}$		0.4	0.8	mA	All inputs at logic low
Quiescent Output Supply Current	$I_{DDO(Q)}$		0.5	0.6	mA	All inputs at logic low
Dynamic Input Supply Current	$I_{DDI(D)}$		0.19		mA/Mbps	
Dynamic Output Supply Current	$I_{DDO(D)}$		0.05		mA/Mbps	
AC SPECIFICATIONS						
Output Rise/Fall Time	t_R/t_F					10% to 90%
A Grade			10		ns	
B Grade			2.5		ns	
Common-Mode Transient Immunity ²	$ CM $	25	35		kV/ μs	$V_{Ix} = V_{DDx}$, $V_{CM} = 1000\text{ V}$, transient magnitude = 800 V
Refresh Rate	f_r		1.2		Mbps	

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¹ I_{Ox} is the Channel x output current, where x = A or B, $V_{I_{xH}}$ is the input side logic high, and $V_{I_{xL}}$ is the input side logic low.

² $|CM|$ is the maximum common-mode voltage slew rate that can be sustained while maintaining $V_O > 0.8 V_{DD}$. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—3.3 V OPERATION

All voltages are relative to their respective grounds. $3.0 V \leq V_{DD1} \leq 3.6 V$, $3.0 V \leq V_{DD2} \leq 3.6 V$. All minimum/maximum specifications apply over the entire recommended operation range, unless otherwise noted. All typical specifications are at $T_A = 25^\circ C$, $V_{DD1} = V_{DD2} = 3.3 V$.

Table 4.

		A Grade			B Grade				
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit	Test Conditions/Comments
SWITCHING SPECIFICATIONS									$C_L = 15\text{ pF}$, CMOS levels
Pulse Width	PW	1000			100			ns	Within PWD limit
Data Rate				1			10	Mbps	Within PWD limit
Propagation Delay	t_{PHL} , t_{PLH}	20		150	20		60	ns	50% input to 50% output
Pulse Width Distortion	PWD								$ t_{\text{PLH}} - t_{\text{PHL}} $
A Grade and B Grade				40			3	ns	$ t_{\text{PLH}} - t_{\text{PHL}} $
WA Grade and WB Grade				40			4	ns	
Change vs. Temperature						5		ps/°C	
Propagation Delay Skew	t_{PSK}			100			22	ns	
Channel Matching									
Codirectional	t_{PSKCD}			50			3	ns	Between any two units
Opposing Directional	t_{PSKOD}			50			22	ns	

Table 5.

		1 Mbps—A Grade, B Grade			10 Mbps—B Grade			
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit
SUPPLY CURRENT (NO LOAD)								
ADuM2200	I _{DD1}		0.8	1.3		2.2	3.2	mA
	I _{DD2}		0.7	1.0		1.3	1.7	mA
ADuM2201	I _{DD1}		0.7	1.3		1.9	2.5	mA
	I _{DD2}		0.8	1.6		1.9	2.5	mA

Table 6.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
DC SPECIFICATIONS						
Logic High Input Threshold	V_{IH}	$0.7 V_{DDx}$			V	
Logic Low Input Threshold	V_{IL}			$0.3 V_{DDx}$	V	
Logic High Output Voltages	V_{OH}	$V_{DDx} - 0.1$	3.0		V	$I_{Ox} = -20 \mu A$, $V_{Ix} = V_{IxH}$
		$V_{DDx} - 0.5$	2.8		V	$I_{Ox} = -3.2 \text{ mA}$, $V_{Ix} = V_{IxH}$
Logic Low Output Voltages	V_{OL}		0.0	0.1	V	$I_{Ox} = 20 \mu A$, $V_{Ix} = V_{IxL}$
			0.2	0.4	V	$I_{Ox} = 3.2 \text{ mA}$, $V_{Ix} = V_{IxL}$
Input Current per Channel	I_I	-10	+0.01	+10	μA	$0 V \leq V_{Ix} \leq V_{DDx}$
Supply Current per Channel						
Quiescent Input Supply Current	$I_{DDI(Q)}$		0.3	0.5	mA	All inputs at logic low
Quiescent Output Supply Current	$I_{DDO(Q)}$		0.3	0.5	mA	All inputs at logic low
Dynamic Input Supply Current	$I_{DDI(D)}$		0.10		mA/Mbps	
Dynamic Output Supply Current	$I_{DDO(D)}$		0.03		mA/Mbps	
AC SPECIFICATIONS						
Output Rise/Fall Time	t_R/t_F					10% to 90%

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Table 6. (Continued)

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
A Grade			10		ns	
B Grade			3		ns	
Common-Mode Transient Immunity ²	CM	25	35		kV/μs	$V_{IX} = V_{DDX}$, $V_{CM} = 1000$ V, transient magnitude = 800 V
Refresh Rate	f_r		1.1		Mbps	

¹ I_{OX} is the Channel x output current, where x = A or B, V_{IXH} is the input side logic high, and V_{IXL} is the input side logic low.

² |CM| is the maximum common-mode voltage slew rate that can be sustained while maintaining $V_O > 0.8 V_{DD}$. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—MIXED 5 V/3.3 V OPERATION

All voltages are relative to their respective grounds. $4.5\text{ V} \leq V_{DD1} \leq 5.5\text{ V}$, $3.0\text{ V} \leq V_{DD2} \leq 3.6\text{ V}$. All minimum/maximum specifications apply over the entire recommended operation range, unless otherwise noted. All typical specifications are at $T_A = 25^\circ\text{C}$, $V_{DD1} = 3.3\text{ V}$, $V_{DD2} = 5.0\text{ V}$.

Table 7.

Parameter	Symbol	A Grade			B Grade			Unit	Test Conditions/ Comments
		Min	Typ	Max	Min	Typ	Max		
SWITCHING SPECIFICATIONS									
Pulse Width	PW	1000			100			ns	C _L = 15 pF, CMOS levels
Data Rate			1				10	Mbps	Within PWD limit
Propagation Delay	t _{PHL} , t _{PLH}	15		150	15		55	ns	50% input to 50% output
Pulse Width Distortion	PWD								t _{PLH} - t _{PHL}
A Grade and B Grade				40			3	ns	
WA Grade and WB Grade				40			4	ns	
Change vs. Temperature						5		ps/°C	
Propagation Delay Skew	t _{PSK}			50			22	ns	Between any two units
Channel Matching									
Codirectional	t _{PSKCD}			50			3	ns	
Opposing Directional	t _{PSKOD}			50			22	ns	

Table 8.

		1 Mbps—A Grade, B Grade			10 Mbps—B Grade			
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit
SUPPLY CURRENT (NO LOAD)								
ADuM2200	I _{DD1}		1.3	1.8		3.5	4.6	mA
	I _{DD2}		0.7	1.0		1.3	1.7	mA
ADuM2201	I _{DD1}		1.1	1.6		3.1	4.2	mA
	I _{DD2}		0.8	1.6		1.9	2.5	mA

Table 9.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
DC SPECIFICATIONS						
Logic High Input Threshold	V_{IH}	$0.7 V_{DDX}$			V	
Logic Low Input Threshold	V_{IL}			$0.3 V_{DDX}$	V	
Logic High Output Voltages	V_{OH}	$V_{DDX} - 0.1$	V_{DDX}		V	$I_{OX} = -20\text{ }\mu\text{A}$, $V_{IX} = V_{IXH}$
		$V_{DDX} - 0.5$	$V_{DDX} - 0.2$		V	$I_{OX} = -3.2\text{ mA}$, $V_{IX} = V_{IXH}$
Logic Low Output Voltages	V_{OL}		0.0	0.1	V	$I_{OX} = 20\text{ }\mu\text{A}$, $V_{IX} = V_{IXL}$
			0.2	0.4	V	$I_{OX} = 3.2\text{ mA}$, $V_{IX} = V_{IXL}$

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Table 9. (Continued)

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
Input Current per Channel	I_I	-10	+0.01	+10	μA	$0\text{ V} \leq V_{IX} \leq V_{DDX}$
Supply Current per Channel						
Quiescent Input Supply Current	$I_{DDI(Q)}$		0.4	0.8	mA	All inputs at logic low
Quiescent Output Supply Current	$I_{DDO(Q)}$		0.3	0.5	mA	All inputs at logic low
Dynamic Input Supply Current	$I_{DDI(D)}$		0.19		mA/Mbps	
Dynamic Output Supply Current	$I_{DDO(D)}$		0.03		mA/Mbps	
AC SPECIFICATIONS						
Output Rise/Fall Time	t_R/t_F					10% to 90%
A Grade			10		ns	
B Grade			3		ns	
Common-Mode Transient Immunity ²	$ CM $	25	35		kV/ μs	$V_{IX} = V_{DDX}$, $V_{CM} = 1000\text{ V}$, transient magnitude = 800 V
Refresh Rate	f_r		1.2		Mbps	

¹ I_{OX} is the Channel x output current, where x = A or B, V_{IXH} is the input side logic high, and V_{IXL} is the input side logic low.

² $|CM|$ is the maximum common-mode voltage slew rate that can be sustained while maintaining $V_O > 0.8 V_{DD}$. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

ELECTRICAL CHARACTERISTICS—MIXED 3.3 V/5 V OPERATION

All voltages are relative to their respective grounds. $3.0\text{ V} \leq V_{DD1} \leq 3.6\text{ V}$, $4.5\text{ V} \leq V_{DD2} \leq 5.5\text{ V}$. All minimum/maximum specifications apply over the entire recommended operation range, unless otherwise noted. All typical specifications are at $T_A = 25^\circ\text{C}$, $V_{DD1} = 5.0\text{ V}$, $V_{DD2} = 3.3\text{ V}$.

Table 10.

		A Grade			B Grade				
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit	Test Conditions/Comments
SWITCHING SPECIFICATIONS									
Pulse Width	PW	1000			100			ns	$C_L = 15\text{ pF}$, CMOS levels
Data Rate			1			10		Mbps	Within PWD limit
Propagation Delay	t_{PHL}, t_{PLH}	15	150		15	55		ns	50% input to 50% output
Pulse Width Distortion	PWD								$ t_{PLH} - t_{PHL} $
A Grade and B Grade			40			3		ns	
WA Grade and WB Grade			40			4		ns	
Change vs. Temperature					5			ps/°C	
Propagation Delay Skew	t_{PSK}		50			22		ns	Between any two units
Channel Matching									
Codirectional	t_{PSKCD}		50			3		ns	
Opposing Directional	t_{PSKOD}		50			22		ns	

Table 11.

		1 Mbps—A Grade, B Grade			10 Mbps—B Grade			
Parameter	Symbol	Min	Typ	Max	Min	Typ	Max	Unit
SUPPLY CURRENT (NO LOAD)								
ADuM2200	I _{DD1}		0.8	1.3		2.2	3.2	mA
	I _{DD2}		1.0	1.6		2.0	2.8	mA
ADuM2201	I _{DD1}		0.7	1.3		1.9	2.5	mA
	I _{DD2}		1.3	1.9		3.1	4.0	mA

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Table 12.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments ¹
DC SPECIFICATIONS						
Logic High Input Threshold	V_{IH}	$0.7 V_{DDx}$			V	
Logic Low Input Threshold	V_{IL}			$0.3 V_{DDx}$	V	
Logic High Output Voltages	V_{OH}	$V_{DDx} - 0.1$	V_{DDx}		V	$I_{Ox} = -20 \mu A$, $V_{Ix} = V_{IxH}$
		$V_{DDx} - 0.5$	$V_{DDx} - 0.2$		V	$I_{Ox} = -3.2 \text{ mA}$, $V_{Ix} = V_{IxH}$
					V	$I_{Ox} = 20 \mu A$, $V_{Ix} = V_{IxL}$
Logic Low Output Voltages	V_{OL}		0.0	0.1	V	$I_{Ox} = 20 \mu A$, $V_{Ix} = V_{IxL}$
			0.2	0.4	V	$I_{Ox} = 3.2 \text{ mA}$, $V_{Ix} = V_{IxL}$
					V	$0 V \leq V_{Ix} \leq V_{DDx}$
Input Current per Channel	I_I	-10	+0.01	+10	μA	
Supply Current per Channel						
Quiescent Input Supply Current	$I_{DDI(Q)}$		0.3	0.5	mA	All inputs at logic low
Quiescent Output Supply Current	$I_{DDO(Q)}$		0.5	0.6	mA	All inputs at logic low
Dynamic Input Supply Current	$I_{DDI(D)}$		0.10		mA/Mbps	
Dynamic Output Supply Current	$I_{DDO(D)}$		0.05		mA/Mbps	
AC SPECIFICATIONS						
Output Rise/Fall Time	t_R/t_F					10% to 90%
A Grade			10		ns	
B Grade			2.5		ns	
Common-Mode Transient Immunity ²	$ CM $	25	35		kV/ μs	$V_{Ix} = V_{DDx}$, $V_{CM} = 1000 \text{ V}$, transient magnitude = 800 V
Refresh Rate	f_r		1.1		Mbps	

¹ I_{Ox} is the Channel x output current, where x = A or B, V_{IxH} is the input side logic high, and V_{IxL} is the input side logic low.

² $|CM|$ is the maximum common-mode voltage slew rate that can be sustained while maintaining $V_O > 0.8 V_{DD}$. The common-mode voltage slew rates apply to both rising and falling common-mode voltage edges.

PACKAGE CHARACTERISTICS

Table 13.

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions/Comments
Resistance (Input-to-Output) ¹	R_{I-O}		10^{12}		Ω	
Capacitance (Input-to-Output) ¹	C_{I-O}		2		pF	$f = 1 \text{ MHz}$
Input Capacitance ²	C_I		4		pF	
IC Junction-to-Ambient Thermal Resistance	θ_{JA}		45		$^{\circ}C/W$	

¹ This device is considered a 2-terminal device: Pin 1 through Pin 8 are shorted together, and Pin 9 through Pin 16 are shorted together.

² Input capacitance is from any input data pin to ground.

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REGULATORY INFORMATION

The ADuM2200/ADuM2201 certification approvals are listed in [Table 14](#). Refer to [Table 19](#) and the [Insulation Lifetime](#) section for more information about the recommended maximum working voltages for specific cross-isolation waveforms and insulation levels.

Table 14. ADuM2200/ADuM2201 Regulatory Information Table

UL	CSA	CQC	VDE
UL 1577 ¹ Single Protection, 5000 V rms	RI-16-2 Package IEC/EN/CSA 62368-1 Basic insulation, 870 V rms Reinforced insulation, 435 V rms IEC/CSA 60601-1 Reinforced insulation (2 MOPP), 250 V rms IEC/CSA 61010-1 Basic insulation, 600 V rms, overvoltage category IV Reinforced insulation, 300 V rms, overvoltage category II RW-16 Package IEC/EN/CSA 62368-1 Basic insulation, 780 V rms Reinforced insulation, 390 V rms IEC/CSA 60601-1 Reinforced insulation (2 MOPP), 125 V rms IEC/CSA 61010-1 Basic insulation, 600 V rms, overvoltage category III Reinforced insulation, 300 V rms, overvoltage category II	CQC GB4943.1 RI-16-2 Package Basic Insulation, 600 V rms Reinforced insulation, 400 V rms RW-16 package Basic Insulation, 600 V rms Reinforced insulation, 380 V rms	DIN EN IEC 60747-17 (VDE 0884-17) RI-16-2 Package ² Reinforced insulation, 645 V peak RW-16 Package ³ Reinforced insulation, 645 V peak
File E214100	Certificate No. 205078	Certificate No. CQC14001105917	Certificate No. 40011599

¹ In accordance with UL 1577, each ADuM2200/ADuM2201 is proof tested by applying an insulation test voltage ≥ 6000 V rms for 1 sec (current leakage detection limit = 10 μ A).

² In accordance with DIN EN IEC 60747-17 (VDE 0884-17), each ADuM2200/ADuM2201 RI-16-2 is proof tested by applying an insulation test voltage ≥ 1209 V peak for 1 sec (partial discharge detection limit = 5 pC). The asterisk (*) marking branded on the components designates DIN EN IEC 60747-17 (VDE 0884-17) approval.

³ In accordance with DIN EN IEC 60747-17 (VDE 0884-17), each ADuM2200/ADuM2201 RW-16 is proof tested by applying an insulation test voltage ≥ 1209 V peak for 1 sec (partial discharge detection limit = 5 pC). The asterisk (*) marking branded on the components designates DIN EN IEC 60747-17 (VDE 0884-17) approval.

SPECIFICATIONS

INSULATION AND SAFETY-RELATED SPECIFICATIONS

Table 15.

Parameter	Symbol	Value	Unit	Test Conditions/Comments
Rated Dielectric Insulation Voltage		5000	V rms	1-minute duration
Minimum External Air Gap (Clearance) ^{1, 2}	L(I01)			Distance measured from input terminals to output terminals, shortest distance through air along the PCB mounting plane, as an aid to PC board layout
RW-16 Package		7.8	mm	
RI-16-2 Package		8.7	mm	
Minimum External Tracking (Creepage) ¹	L(I02)			Measured from input terminals to output terminals, shortest distance path along body
RW-16 Package		7.8	mm	
RI-16-2 Package		8.7	mm	
Minimum Internal Distance (Internal Clearance)		18	um	Insulation distance through insulation
Tracking Resistance (Comparative Tracking Index) ³	CTI	>400	V	DIN IEC 112/VDE 0303, Part 1
Isolation Group		II		Material Group (DIN VDE 0110, 1/89, Table 1)

¹ In accordance with IEC 62368-1 / IEC 60601-1 guidelines for the measurement of creepage and clearance distances for a pollution degree of 2 and altitudes ≤2000 m.

² Consideration must be given to pad layout to ensure the minimum required distance for clearance is maintained.

³ CTI rating for the ADuM2200/ADuM2201 RI-16-2/ADuM2200/ADuM2201 RW_16 is >400 V and a Material Group II isolation group.

DIN EN IEC 60747-17 (VDE 0884-17) INSULATION CHARACTERISTICS

These isolators are suitable for reinforced electrical isolation only within the safety limit data. Maintenance of the safety data is ensured by means of protective circuits. The asterisk (*) marking branded on the components designates DIN EN IEC 60747-17 (VDE 0884-17) approval.

Table 16. ADuM2200/ADuM2201 VDE Insulation Characteristics

Description	Test Conditions/Comments	Symbol	Characteristic	Unit
Overvoltage Category per IEC 60664-1			I to IV	
≤ 150 V rms			I to IV	
≤ 300 V rms			I to IV	
≤ 400 V rms			I to IV	
Climatic Classification			40/105/21	
Pollution Degree per DIN VDE 0110, Table 1			2	
Maximum Repetitive Isolation Voltage		V _{IORM}	645	V peak
Maximum Working Isolation Voltage		V _{IOWM}	456	V rms
Input-to-Output Test Voltage, Method B1	V _{IORM} × 1.875 = V _{pd(m)} , 100% production test, t _{ini} = t _m = 1 sec, partial discharge < 5 pC	V _{pd(m)}	1209	V peak
Input-to-Output Test Voltage, Method A				
After Environmental Tests Subgroup 1	V _{IORM} × 1.6 = V _{pd(m)} , t _{ini} = 60 sec, t _m = 10 sec, partial discharge < 5 pC	V _{pd(m)}	1032	V peak
After Input and/or Safety Tests Subgroup 2 and Subgroup 3	V _{IORM} × 1.2 = V _{pd(m)} , t _{ini} = 60 sec, t _m = 10 sec, partial discharge < 5 pC	V _{pd(m)}	774	V peak
Maximum Transient Isolation Voltage	V _{TEST} = 1.2 × V _{IOTM} , t = 1s (100% production)	V _{IOTM}	6000	V peak
Maximum Impulse Voltage	Surge voltage in air, waveform per IEC 61000-4-5	V _{IMP}	6000	V peak
Maximum Surge Isolation Voltage	V _{TEST} ≥ 1.3 × V _{IMP} (sample test), tested in oil, waveform per IEC 61000-4-5	V _{IOSM}	10000	V peak
Safety Limiting Values	Maximum value allowed in the event of a failure; see Figure 3			
Maximum Junction Temperature		T _S	150	°C
Total Power Dissipation at 25°C		P _S	2.78	W
Insulation Resistance at T _S	V _{IO} = 500 V	R _S	>10 ⁹	Ω

SPECIFICATIONS

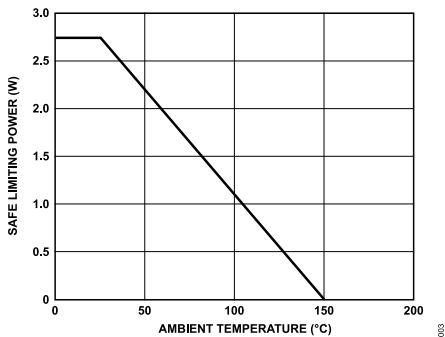


Figure 3. Thermal Derating Curve, Dependence of Safety Limiting Values with Case Temperature per DIN EN IEC 60747-17 (VDE 0884-17)

RECOMMENDED OPERATING CONDITIONS

Table 17.

Parameter	Symbol	Min	Max	Unit
Operating Temperature	T _A			
A Grade and B Grade		−40	+105	°C
WA Grade and WB Grade		−40	+125	°C
Supply Voltages ¹	V _{DD1} , V _{DD2}	3.0	5.5	V
Input Signal Rise and Fall Times			1.0	ms

¹ All voltages are relative to their respective grounds.

ABSOLUTE MAXIMUM RATINGS

Table 18.

Parameter	Rating
Storage Temperature (T_{ST})	-65°C to +150°C
Ambient Operating Temperature (T_A)	-40°C to +125°C
Supply Voltage (V_{DD1} , V_{DD2}) ¹	-0.5 V to +7.0 V
Input Voltage (V_{IA} , V_{IB}) ^{1, 2}	-0.5 V to V_{DD1} + 0.5 V
Output Voltage (V_{OA} , V_{OB}) ^{1, 2}	-0.5 V to V_{DDO} + 0.5 V
Average Output Current per Pin ³	
Side 1 (I_{O1})	-18 mA to +18 mA
Side 2 (I_{O2})	-22 mA to +22 mA
Common-Mode Transients ⁴	-100 kV/μs to +100 kV/μs

¹ All voltages are relative to their respective grounds.

² V_{DD1} and V_{DDO} refer to the supply voltages on the input and output sides of a given channel, respectively. See the [PCB Layout](#) section.

³ See [Figure 3](#) for maximum rated current values for various temperatures.

⁴ Refers to common-mode transients across the insulation barrier. Common-mode transients exceeding the absolute maximum rating can cause latch-up or permanent damage.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other

conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

MAXIMUM CONTINUOUS WORKING VOLTAGE

Table 19. Maximum Continuous Working Voltage

Parameter	Max	Unit	Applicable Certification
AC Voltage			
Bipolar Waveform	645	V peak	Reinforced insulation rating per IEC 60747-17 (VDE 0884-17) ¹

¹ Refers to the continuous voltage magnitude imposed across the isolation barrier. See the [Insulation Lifetime](#) section for more details.

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

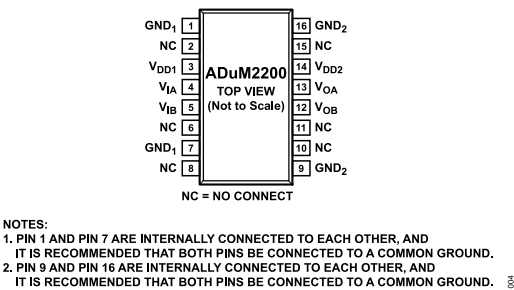


Figure 4. ADuM2200 Pin Configuration

Table 20. ADuM2200 Pin Function Descriptions

Pin No.	Mnemonic	Description
1, 7	GND ₁	Ground 1. Ground reference for Isolator Side 1. Pin 1 and Pin 7 are internally connected to each other, and it is recommended that both pins be connected to a common ground.
2	NC	No Internal Connection.
3	V _{DD1}	Supply Voltage for Isolator Side 1, 3.0 V to 5.5 V.
4	V _{IA}	Logic Input A.
5	V _{IB}	Logic Input B.
6	NC	No Internal Connection.
8	NC	No Internal Connection.
9, 16	GND ₂	Ground 2. Ground reference for Isolator Side 2. Pin 9 and Pin 16 are internally connected to each other, and it is recommended that both pins be connected to a common ground.
10	NC	No Internal Connection.
11	NC	No Internal Connection.
12	V _{OB}	Logic Output B.
13	V _{OA}	Logic Output A.
14	V _{DD2}	Supply Voltage for Isolator Side 2, 3.0 V to 5.5 V.
15	NC	No Internal Connection.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

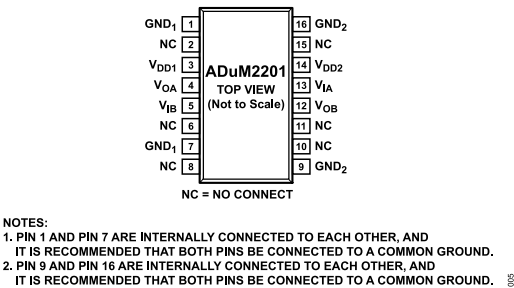


Figure 5. ADuM2201 Pin Configuration

Table 21. ADuM2201 Pin Function Descriptions

Pin No.	Mnemonic	Description
1, 7	GND ₁	Ground 1. Ground reference for Isolator Side 1. Pin 1 and Pin 7 are internally connected to each other, and it is recommended that both pins be connected to a common ground.
2	NC	No Internal Connection.
3	V _{DD1}	Supply Voltage for Isolator Side 1, 3.0 V to 5.5 V.
4	V _{OA}	Logic Output A.
5	V _{IB}	Logic Input B.
6	NC	No Internal Connection.
8	NC	No Internal Connection.
9, 16	GND ₂	Ground 2. Ground reference for Isolator Side 2. Pin 9 and Pin 16 are internally connected to each other, and it is recommended that both pins be connected to a common ground.
10	NC	No Internal Connection.
11	NC	No Internal Connection.
12	V _{OB}	Logic Output B.
13	V _{IA}	Logic Input A.
14	V _{DD2}	Supply Voltage for Isolator Side 2, 3.0 V to 5.5 V.
15	NC	No Internal Connection.

TYPICAL PERFORMANCE CHARACTERISTICS

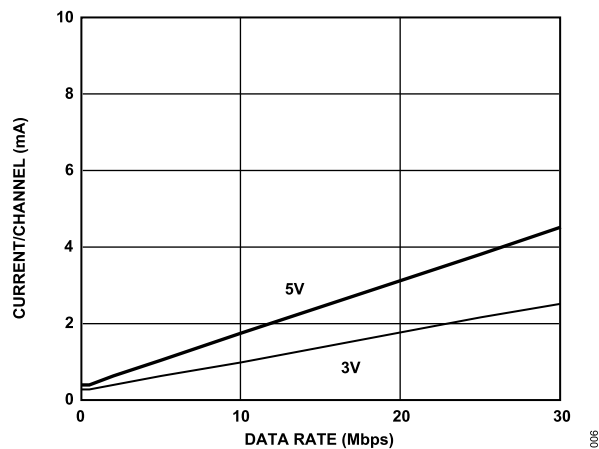


Figure 6. Typical Input Supply Current per Channel vs. Data Rate for 5 V and 3.3 V Operation (No Output Load)

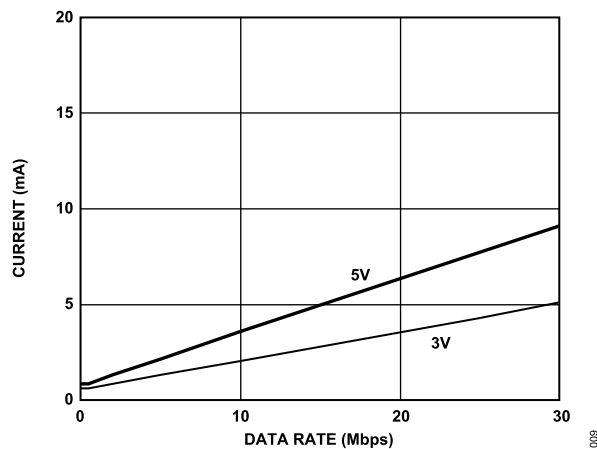


Figure 9. Typical ADuM2200 V_{DD1} Supply Current vs. Data Rate for 5 V and 3.3 V Operation

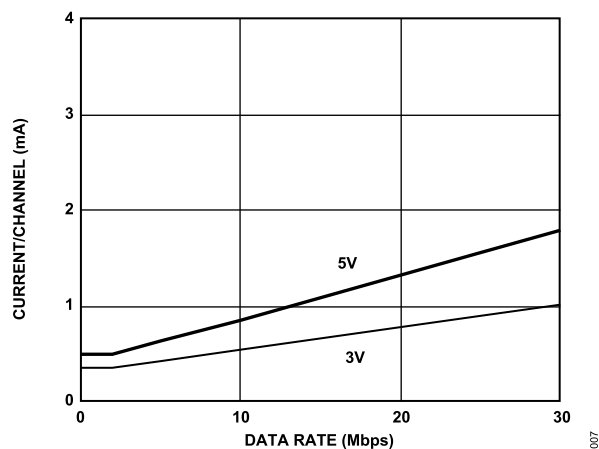


Figure 7. Typical Output Supply Current per Channel vs. Data Rate for 5 V and 3.3 V Operation (No Output Load)

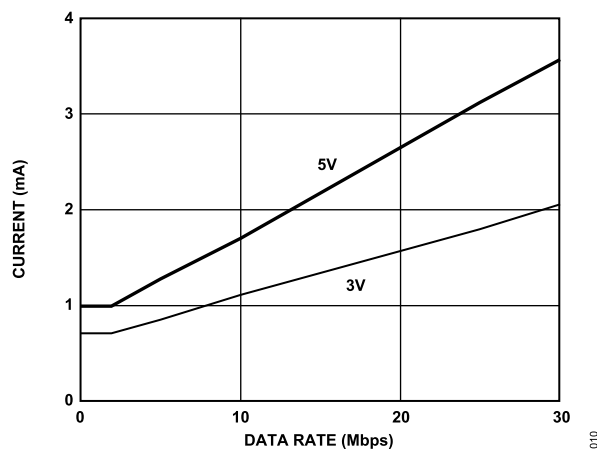


Figure 10. Typical ADuM2200 V_{DD2} Supply Current vs. Data Rate for 5 V and 3.3 V Operation

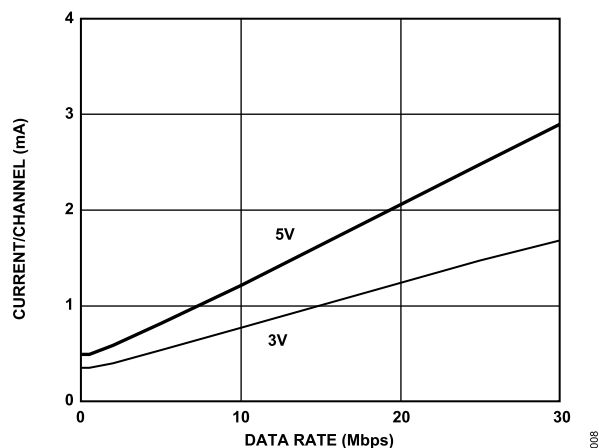


Figure 8. Typical Output Supply Current per Channel vs. Data Rate for 5 V and 3.3 V Operation (15 pF Output Load)

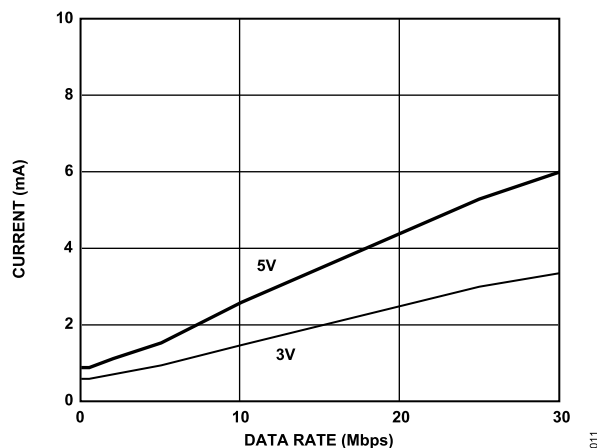


Figure 11. Typical ADuM2201 V_{DD1} or V_{DD2} Supply Current vs. Data Rate for 5 V and 3.3 V Operation

APPLICATIONS INFORMATION

PCB LAYOUT

The ADuM2200/ADuM2201 digital isolators require no external interface circuitry for the logic interfaces. Power supply bypassing is strongly recommended at the input and output supply pins (see [Figure 12](#)). Bypass capacitors are most conveniently connected between Pin 1 and Pin 3 for V_{DD1} and between Pin 14 and Pin 16 for V_{DD2} . The capacitor value should be between 0.01 μF and 0.1 μF . The total lead length between both ends of the capacitor and the input power supply pin should not exceed 2 mm. Consider bypassing between Pin 3 and Pin 7 and between Pin 9 and Pin 14 unless the ground pair on each package side is connected close to the package.

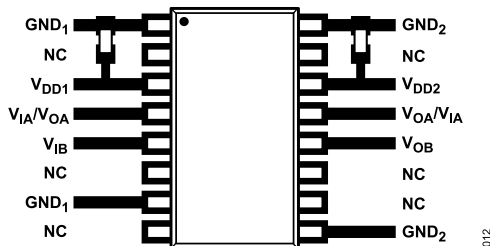


Figure 12. Recommended Printed Circuit Board Layout

In applications involving high common-mode transients, ensure that board coupling across the isolation barrier is minimized. Furthermore, design the board layout such that any coupling that does occur affects all pins equally on a given component side. Failure to ensure this can cause voltage differentials between pins exceeding the absolute maximum ratings for the device as specified in [Table 18](#), thereby leading to latch-up or permanent damage.

See the [AN-1109 Application Note](#) for board layout guidelines.

PROPAGATION DELAY-RELATED PARAMETERS

Propagation delay is a parameter that describes the length of time it takes for a logic signal to propagate through a component. The propagation delay to a logic low output can differ from the propagation delay to a logic high output.

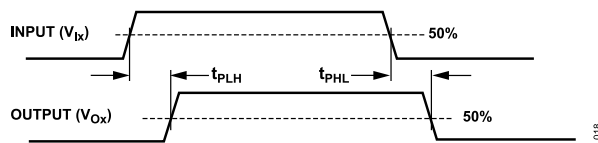


Figure 13. Propagation Delay Parameters

Pulse width distortion is the maximum difference between these two propagation delay values and is an indication of how accurately the timing of the input signal is preserved.

Channel-to-channel matching refers to the maximum amount that the propagation delay differs between channels within a single ADuM2200/ADuM2201 component.

Propagation delay skew refers to the maximum amount that the propagation delay differs between multiple ADuM2200/ADuM2201 components operated under the same conditions.

DC CORRECTNESS AND MAGNETIC FIELD IMMUNITY

Positive and negative logic transitions at the isolator input cause narrow (~ 1 ns) pulses to be sent to the decoder via the transformer. The decoder is bistable and is, therefore, either set or reset by the pulses, indicating input logic transitions. In the absence of logic transitions at the input for more than ~ 1 μs , a periodic set of refresh pulses indicative of the correct input state is sent to ensure dc correctness at the output. If the decoder receives no internal pulses for more than approximately 5 μs , the input side is assumed to be unpowered or nonfunctional, and the isolator output is forced to a default state by the watchdog timer circuit (see [Table 21](#) and [#unique_5/unique_5_Connect_42_ID3703](#)).

The limitation on the magnetic field immunity of the ADuM2200/ADuM2201 is set by the condition in which induced voltage in the transformer receiving coil is large enough to either falsely set or reset the decoder. The following analysis defines the conditions under which this can occur. The 3.3 V operating condition of the ADuM2200/ADuM2201 is examined because it represents the most susceptible mode of operation.

The pulses at the transformer output have an amplitude greater than 1.0 V. The decoder has a sensing threshold at approximately 0.5 V, thus establishing a 0.5 V margin in which induced voltages can be tolerated. The voltage induced across the receiving coil is given by

$$V = (-d\beta/dt) \sum \pi r_n^2; n = 1, 2, \dots, N \quad (1)$$

where:

β is the magnetic flux density (gauss).

r_n is the radius of the n^{th} turn in the receiving coil (cm).

N is the number of turns in the receiving coil.

Given the geometry of the receiving coil in the ADuM2200/ADuM2201 and an imposed requirement that the induced voltage be, at most, 50% of the 0.5 V margin at the decoder, a maximum allowable magnetic field is calculated as shown in [Figure 14](#).

APPLICATIONS INFORMATION

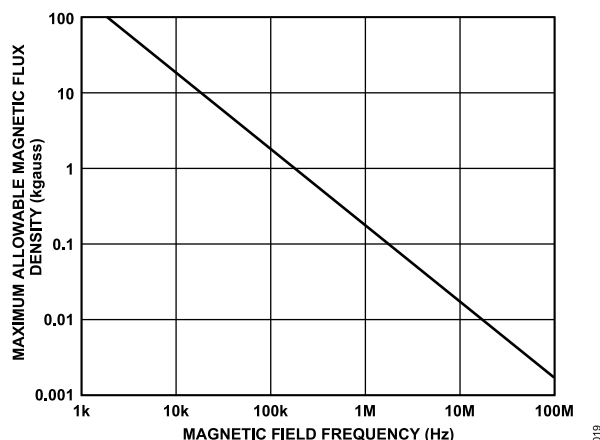


Figure 14. Maximum Allowable External Magnetic Flux Density

For example, at a magnetic field frequency of 1 MHz, the maximum allowable magnetic field of 0.2 kgauss induces a voltage of 0.25 V at the receiving coil. This voltage is approximately 50% of the sensing threshold and does not cause a faulty output transition. Similarly, if such an event occurs during a transmitted pulse (and is of the worst-case polarity), it reduces the received pulse from >1.0 V to 0.75 V—still well above the 0.5 V sensing threshold of the decoder.

The preceding magnetic flux density values correspond to specific current magnitudes at given distances from the ADuM2200/ADuM2201 transformers. Figure 15 expresses these allowable current magnitudes as a function of frequency for selected distances. As shown in Figure 15, the ADuM2200/ADuM2201 are immune and can be affected only by extremely large currents operated at high frequency very close to the component. For the 1 MHz example noted, a 0.5 kA current placed 5 mm away from the ADuM2200/ADuM2201 is required to affect the operation of the component.

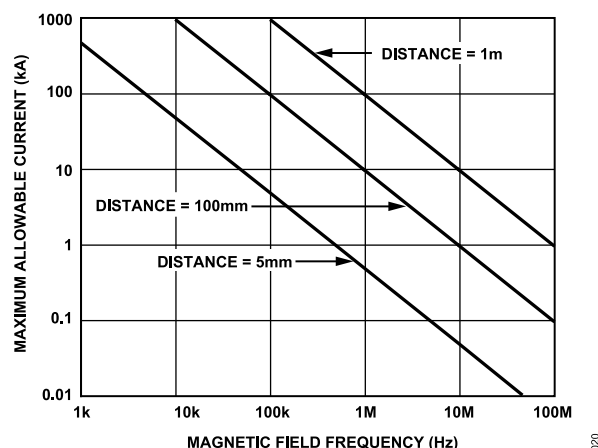


Figure 15. Maximum Allowable Current for Various Current-to-ADuM2200/ADuM2201 Spacings

Note that at combinations of strong magnetic field and high frequency, any loops formed by printed circuit board traces can induce error voltages sufficiently large to trigger the thresholds of succeed-

ing circuitry. Care should be taken in the layout of such traces to avoid this possibility.

POWER CONSUMPTION

The supply current at a given channel of the ADuM2200/ADuM2201 isolators is a function of the supply voltage, the channel data rate, and the channel output load.

For each input channel, the supply current is given by

$$I_{DDI} = I_{DDI(Q)} \quad f \leq 0.5f_r \quad (2)$$

$$I_{DDI} = I_{DDI(D)} \times (2f - f_r) + I_{DDI(Q)} \quad f > 0.5f_r \quad (3)$$

For each output channel, the supply current is given by

$$I_{DDO} = I_{DDO(Q)} \quad f \leq 0.5f_r \quad (4)$$

$$I_{DDO} = (I_{DDO(D)} + (0.5 \times 10^{-3}) \times C_L \times V_{DDO}) \times (2f - f_r) + I_{DDO(Q)} \quad f > 0.5f_r \quad (5)$$

where:

$I_{DDI(D)}$, $I_{DDO(D)}$ are the input and output dynamic supply currents per channel (mA/Mbps).

$I_{DDI(Q)}$, $I_{DDO(Q)}$ are the specified input and output quiescent supply currents (mA).

C_L is the output load capacitance (pF).

V_{DDO} is the output supply voltage (V).

f is the input logic signal frequency (MHz, half of the input data rate, NRZ signaling).

f_r is the input stage refresh rate (Mbps).

To calculate the total I_{DD1} and I_{DD2} , the supply currents for each input and output channel corresponding to I_{DD1} and I_{DD2} are calculated and totaled.

Figure 6 and Figure 7 provide per-channel supply currents as a function of data rate for an unloaded output condition. Figure 8 provides per-channel supply current as a function of data rate for a 15 pF output condition. Figure 9 through Figure 11 provide total I_{DD1} and I_{DD2} as a function of data rate for the ADuM2200/ADuM2201 channel configurations.

APPLICATIONS INFORMATION

INSULATION LIFETIME

All insulation structures eventually break down when subjected to voltage stress over a sufficiently long period. The rate of insulation degradation is dependent on the characteristics of the voltage waveform applied across the insulation. In addition to the testing performed by the regulatory agencies, Analog Devices carries out an extensive set of evaluations to determine the lifetime of the insulation structure within the ADuM2200/ADuM2201 devices.

Accelerated life testing is performed using voltage levels higher than the rated continuous working voltage. Acceleration factors for several operating conditions are determined, allowing calculation of the time to failure at the working voltage of interest. The values shown in [Table 19](#) summarize the maximum continuous working voltages as per IEC 60747-17. Operation at working voltages higher than the service life voltage listed leads to premature insulation failure.

OUTLINE DIMENSIONS

Package Drawing (Option)	Package Type	Package Description
RW-16	SOIC_W	16-Lead Standard Small Outline Package
RI-16-2	SOIC_IC	16-Lead Standard Small Outline Package, with Increased Creepage

For the latest package outline information and land patterns (footprints), go to [Package Index](#).

ORDERING GUIDE

Model ^{1, 2, 3}	Temperature Range	Package Description	Package Option
ADuM2200ARIZ	-40°C to +105°C	16-Lead SOIC_IC	RI-16-2
ADuM2200ARWZ	-40°C to +105°C	16-Lead SOIC_W	RW-16
ADuM2200WARWZ	-40°C to +125°C	16-Lead SOIC_W	RW-16
ADuM2200BRIZ	-40°C to +105°C	16-Lead SOIC_IC	RI-16-2
ADuM2200BRWZ	-40°C to +105°C	16-Lead SOIC_W	RW-16
ADuM2200WBRWZ	-40°C to +125°C	16-Lead SOIC_W	RW-16
ADuM2201ARIZ	-40°C to +105°C	16-Lead SOIC_IC	RI-16-2
ADuM2201ARWZ	-40°C to +105°C	16-Lead SOIC_W	RW-16
ADuM2201WARWZ	-40°C to +125°C	16-Lead SOIC_W	RW-16
ADuM2201BRIZ	-40°C to +105°C	16-Lead SOIC_IC	RI-16-2
ADuM2201BRWZ	-40°C to +105°C	16-Lead SOIC_W	RW-16
ADuM2201WBRWZ	-40°C to +125°C	16-Lead SOIC_W	RW-16

¹ Z = RoHS Compliant Part.

² W = Qualified for Automotive Applications.

³ Tape and reel is available. The addition of an -RL suffix designates a 13" (1,000 units) tape and reel option.

NUMBER OF INPUTS, MAXIMUM DATA RATE, MAXIMUM PROPAGATION, AND MAXIMUM PULSE WIDTH DISTORTION OPTIONS

Model ^{1, 2, 3}	Number of Inputs, V _{DD1} Side	Number of Inputs, V _{DD2} Side	Maximum Data Rate (Mbps)	Maximum Propagation Delay, 5 V (ns)	Maximum Pulse Width Distortion (ns)
ADuM2200ARIZ	2	0	1	150	40
ADuM2200ARWZ	2	0	1	150	40
ADuM2200WARWZ	2	0	1	150	40
ADuM2200BRIZ	2	0	10	50	3
ADuM2200BRWZ	2	0	10	50	3
ADuM2200WBRWZ	2	0	10	50	3
ADuM2201ARIZ	1	1	1	150	40
ADuM2201ARWZ	1	1	1	150	40
ADuM2201WARWZ	1	1	1	150	40
ADuM2201BRIZ	1	1	10	50	3
ADuM2201BRWZ	1	1	10	50	3
ADuM2201WBRWZ	1	1	10	50	3

¹ Z = RoHS Compliant Part.

² W = Qualified for Automotive Applications.

³ Tape and reel is available. The addition of an -RL suffix designates a 13" (1,000 units) tape and reel option.

OUTLINE DIMENSIONS

AUTOMOTIVE PRODUCTS

The [ADuM2200W](#) and [ADuM2201W](#) models are available with controlled manufacturing to support the quality and reliability requirements of automotive applications. Note that these automotive models may have specifications that differ from the commercial models; therefore, designers should review the [Specifications](#) section of this data sheet carefully. Only the automotive grade products shown are available for use in automotive applications. Contact your local Analog Devices account representative for specific product ordering information and to obtain the specific Automotive Reliability reports for these models.